

QUERY CONTROL FORM		RTIS USE ONLY	
Application No. <u>09/820,143</u>	Prepared by <u>KW</u>	Tracking Number <u>05888458</u>	
Examiner-GAU <u>2881</u>	Date <u>2/3/04</u>	Week Date <u>1/12/2004</u>	
	No. of queries <u>2 IFW</u>		

## JACKET

- |                      |                        |                    |                    |
|----------------------|------------------------|--------------------|--------------------|
| a. Serial No.        | f. Foreign Priority    | k. Print Claim(s)  | <u>p. PTO-1449</u> |
| b. Applicant(s)      | g. Disclaimer          | l. Print Fig.      | q. PTOL-85b        |
| c. Continuing Data   | h. Microfiche Appendix | m. Searched Column | r. Abstract        |
| d. PCT               | i. Title               | n. PTO-270/328     | s. Sheets/Figs     |
| e. Domestic Priority | j. Claims Allowed      | o. PTO-892         | t. Other           |

## SPECIFICATION

- a. Page Missing
- b. Text Continuity
- c. Holes through Data
- d. Other Missing Text
- e. Illegible Text
- f. Duplicate Text
- g. Brief Description
- h. Sequence Listing
- i. Appendix
- j. Amendments
- k. Other

## CLAIMS

- a. Claim(s) Missing
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- k. Other

## MESSAGE

PTO-1449: Please enter initial or line through citations. (1 page)

Verify Primary Examiner Name. (2 pages)

Thank you

initials KW

## RESPONSE

initials

Form PTO-1449 (MODIFIED)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. 039153-0405 (P0945)		SERIAL NO. 09/820,143		
<b>INFORMATION DISCLOSURE CITATION</b> (Use several sheets if necessary)				APPLICANT Uzodinma Okoranyanwu et al.		<b>RECEIVED</b> TELETYPE UNIT 03/28/2001 2878		
				FILING DATE 03/28/2001				
<b>U.S. PATENT DOCUMENTS</b>								
EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB- CLASS	FILING DATE IF APPROPRIATE	
		09/819,342		Shields et al			03/28/01	
		09/819,343		Gabriel et al			03/28/01	
		09/819,344		Okoranyanwu et al			03/28/01	
		09/819,552		Gabriel et al			03/28/01	
		09/819,692		Okoranyanwu et al			03/28/01	
		6,107,172	08/22/00	Yang et al	438	585		
		6,103,457	08/15/00	Gabriel	430	318		
		5,965,461	10/12/99	Yang et al	438	717		
		5,003,178	03/26/91	Livesay	250	492.300		
<b>FOREIGN PATENT DOCUMENTS</b>								
	REF	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB- CLASS	TRANSLATION	
							YES	NO
<b>OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)</b>								
		Livesay, W. R., "Large-area electron-beam source," Journal of Vacuum Science & Technology B, Vol. 11, No. 6, Nov./Dec. 1993, pp. 2304-2308, American Vacuum Society						
		Yang, J. J. et al, "Electron Beam Processing for Spin-on Polymers and its Applications to Back-End-of-Line (BEOL) Integration," Materials Research Society Symposium Proceedings, Vol. 511, 1998, pp. 49-55, Materials Research Society						
		Ross et al, "Plasma Etch Characteristics of Electron Beam Processed Photoresist," The Society of Photo-Optical Instrumentation Engineers, Vol. 2438, 1995, pp. 803-816, SPIE-The International Society for Optical Engineering						
		Grün, Von A. E., "Lumineszenz-photometrische Messungen der Energieabsorption im Strahlungsfeld von Elektronenquellen Eindimensionaler Fall in Luft," Zeitschrift für Naturforschung, Vol. 12a, 1957, pp. 89-95, Publisher: Zeitschrift für Naturforschung; full English Translation attached (11 pgs.)						
<b>EXAMINER</b>					<b>DATE CONSIDERED</b>			
* <b>EXAMINER:</b> Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include any copy of this form with next communication to applicant.								